

# REGISTRATION FORM

## ASTR 2004 Workshop on Accelerated Stress Testing & Reliability October 6-8, 2004

### **Hotel:**

Holiday Inn Chicago-Mart Plaza  
350 North Orleans Street  
Chicago, IL 60654

### **Hosted By:**

IEEE/CPMT TC-ASTR and Technically co-sponsored by IEEE Reliability Society

### **Conference Overview:**

Over the last few years, Accelerated Stress Testing (AST) has been embraced by an ever widening array of worldwide companies seeking to reconcile the need for the highest quality product with the necessary push for early time-to-market. The purpose of the AST Workshop is to share ideas on better ways of accelerating and detecting hidden defects, flaws, and weaknesses in electronic and electro-mechanical hardware that would result in failures during usage. These techniques are focused on testing electronic hardware to destruction limits and root cause investigation to determine the physics-of-failure. The goal of AST is to produce mature products at market introduction and, in making it robust, the product can be screened for manufacturing defects with high combined stresses (beyond end-use specifications) for shorter lengths of time.

Please see: <http://www.ewh.ieee.org/soc/cpmt/tc7/ast2004/> , for additional AST Conference Highlights.

### **Topics:**

Advanced Approaches to AST  
Reliability Improvement Techniques  
AST Data Collection  
Advanced Data Analysis  
Failure Analysis Techniques  
Reliability Simulation and Modeling  
Physics of Failure Techniques  
Stress Screening Techniques  
AST Case Studies

Stress Selection Amplitudes and Profiles  
Functional Test During Stress Testing  
AST Results on New Technologies  
ESD  
AST on hardware/software interactions  
AST impact on Business and Engineering Decisions  
Equipment and Facility considerations  
Vibration Selection

### **Tutorials:**

The all day tutorial program will be held on the first day of the Workshop and features well respected experts sharing their experiences and hard learned lessons. Two parallel sessions, Basic AST and Advanced AST Subjects, will ensure that experienced practitioners as well as those who are just entering the field will find useful and interesting presentations.

### **Registration:**

Please complete the form below and return with payment to the address specified. You may also fax the registration form to Don Hayward at (360) 705-8686.

For more information, visit:

ASTR 2004 -- <http://www.ewh.ieee.org/soc/cpmt/tc7/ast2004>

CPMT TC-ASTR -- <http://www.ewh.ieee.org/soc/cpmt/tc7>

IEEE Reliability Society -- <http://www.ewh.ieee.org/soc/rs>

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_____	Non member – after Sept. 24	\$ 550.00	_____
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Olympia, WA 98508 USA